Please type a plus sign (+) inside this box → +

Approved for use through 10/31/2001. OMB 0651-0031

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

U.S. Patent and Tracemark Office. U.S. Description of Information unless it contains a valid OMB control number.

Sabstitute for form 1449A/PTO

## MNFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet of

	Complete	e if Known	
ľ	Application Number	10/603,304	
[	Filing Date	June 25, 2003	
[	First Named Inventor	Miyuki MATSUYA	
	Group Art Unit	2881	
$\prod$	Examiner Name	Not Yet Assigned	
T	Attorney Docket Number	0116-031009	

				U.S. PATENT DOCUM			
Examiner Initials*	Cite No.1	U.S. Patent Document  Number Kind Code <sup>2</sup>		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
P6		5,084,622	B1	Rose	01/28/1992		
P6		6,191,423	B1	Krijn et al.	02/20/2001		
.,,,,,							
····	ļ						
	<u> </u>	<u> </u>					
	ļ						
<del></del>	<del> </del>						

FOREIGN PATENT DOCUMENTS									
Examiner	Cite	Foreign Patent Document			Name of Patentee or Date of Publication	Pages, Columns, Lines,			
Initials	No.¹	Office <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>s</sup>	Applicant of Cited Document	of Cited Document	Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>	
	<del> </del>								
	ļ								
	ļ								
	1								
	<u> </u>							4	
		<u> </u>							
		l				[			

Examiner	Yaul Sur		Date	2/11/	25
Signature			Considered	الماال	<i>2</i> 5
*EXAMINER:	Initial if reference considered	whether or not citation is in conformance with MP	EP 609. Draw line through	citation if not in	conformance and not

<sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>3</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. Applicant is to place a check mark here if English language Translation is attached.

Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

considered. Include copy of this form with next communication to applicant.

Under the Paperwork Reduction Act of 1995 no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for	r form 1449A/PTO	)					
				Complete if Known			
INFO	RMAHO	N DISCLO	JSURE	Application Number	10/603,304		
STAT	FMFNT	BY APPL	ICANT	Filing Date	June 25, 2003		
0.71	<b>—</b>	<b>D</b> (		First Named Inventor	Miyuki MATSUYA		
(	use as many sheet	s as necessary)		Group Art Unit	2881		
				Examiner Name	Not Yet Assigned		
Sheet	2	of	2	Attorney Docket Number	0116-031009		

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS									
Examiner Initials*									
P6		VON H. ROSE, <i>OPTIK 33,</i> Heft 1, 1971, pages 1-24.							
76		VON H. ROSE, <i>OPTIK 34,</i> Heft 3, 1971, pages 285-311.							
PG PG PG PG PG PG		E. MUNRO ET AL., "High-resolution, low-energy beams by means of mirror optics", J. Vac. Sci. Technol. B 6 (6), Nov./Dec. 1988, pages 1971-1976.							
76		J. ZACH, "Design of a high-resolution low-voltage scanning electron microscope", OPTIK 83, No. 1 (1989), pages 30-40.							
PF		H. ROSE, "Inhomogeneous Wien filter as a corrector compensating for the chromatic and spherical aberration of low-voltage electron microscopes", <i>OPTIK</i> 84, No. 3 (1990), pages 91-107.							
Po		H. ROSE, "Outline of a spherically corrected semiaplanatic medium-voltage transmission electron microscope", OPTIK 85, No. 1 (1990), pages 19-24.							
Pb		JOACHIM ZACH ET AL., "Aberration correction in a low voltage SEM by a multipole corrector", Nucl. Instr. and Meth. in Phys. Res. A 363 (1995), pages 316-325.							
L									

		1				
Examiner Signature	aul	Hurg	<b>6</b>	Date Considered	3/16/	05
		, , ,				

Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>3</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language Translation is attached.